



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani et al.  
Assignee: KLA-Tencor Corporation  
Title: Sample Inspection System  
Application No.: 10/627,402 Filing Date: July 24, 2003  
Examiner: Not yet assigned Group Art Unit: 2877  
Docket No.: TNCR.152US7 Conf. No.: 2861

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

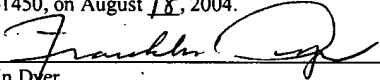
Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant calls the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

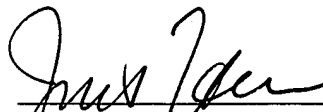
Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed, or were previously submitted in Application Nos. 10/033,069; 09/746,141; and 08/933,771, from which this Application claims an earlier effective filing date.

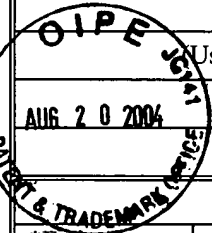
This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

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| <p align="center"><u>Certificate of Mailing Under 37 CFR 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to:<br/>Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August <u>18</u>, 2004.</p> <p><br/>_____<br/>Franklin Dyer</p> |
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Respectfully submitted,

  
\_\_\_\_\_  
James S. Hsue  
Reg. No. 29,545

8/18/04  
\_\_\_\_\_  
Date

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| U.S. Department of Commerce, Patent and Trademark   |    |   |                 | Atty. Docket No.       |       | Application No. |                            |    |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT   |    |   |                 | TNCR.152US7            |       | 10/627,402      |                            |    |
|   |    |   |                 | Applicant(s)           |       | Conf. No.       |                            |    |
| (Use several sheets if necessary)   |    |   |                 | M. Vaez-Iravani et al. |       | 2861            |                            |    |
|   |    |   |                 | Filing Date            |       | Group           |                            |    |
|   |    |   |                 | July 24, 2003          |       | 2877            |                            |    |
| <b>U.S. Patent Documents</b>  |    |   |                 |                        |       |                 |                            |    |
| *Examiner Initial   |    | Document Number   | Date            | Name                   | Class | Subclass        | Filing Date If Appropriate |    |
|   | AA | 4,558,949   | 12/85           | Uehara et al.          |       |                 |                            |    |
|   | AB | 4,893,932   | 1/1990          | Knollenberg            |       |                 |                            |    |
|   | AC | 5,058,982   | 10/1991         | Katzir                 |       |                 |                            |    |
|   | AD | 5,712,701   | 1/98            | Dementi et al.         |       |                 |                            |    |
|   | AE | 5,929,983   | 7/99            | Lu                     |       |                 |                            |    |
|   | AF | 6,118,525   | 9/00            | Fossey et al.          |       |                 |                            |    |
|   | AG | 6,169,601   | 1/01            | Eremin et al.          |       |                 |                            |    |
| <b>U.S. Published Patent Application Documents</b>  |    |   |                 |                        |       |                 |                            |    |
| *Examiner Initial   |    | Document Number   | Date            | Name                   | Class | Subclass        | Filing Date If Appropriate |    |
|   |    |   |                 |                        |       |                 |                            |    |
|   |    |   |                 |                        |       |                 |                            |    |
| <b>Foreign Patent Documents</b>   |    |   |                 |                        |       |                 |                            |    |
|   |    |   |                 |                        |       |                 | Translation                |    |
|   |    | Document  | Date            | Country                | Class | Subclass        | Yes                        | No |
|   | AH | WO97/33158  | 9/1997          | International          |       |                 | X                          |    |
|   | AI | EP0624787   | 11/1994         | Europe                 |       |                 | Abstract                   |    |
|   | AJ | DE4123916   | 1/1992          | German                 |       |                 | Abstract                   |    |
|   | AK | WO97/12226  | 4/1997          | International          |       |                 | X                          |    |
| <b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>   |    |   |                 |                        |       |                 |                            |    |
|   | AL | "Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Electronics Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26  |                 |                        |       |                 |                            |    |
|   | AM | Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 <sup>th</sup> International Workshop on 300 Millimeter Wafers on 12/5/1996 in Makuhari, Japan |                 |                        |       |                 |                            |    |
|   | AN | Partial European Search Report dated October 18, 2000   |                 |                        |       |                 |                            |    |
| Examiner  |    |   | Date Considered |                        |       |                 |                            |    |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant. |    |   |                 |                        |       |                 |                            |    |

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|---|--|--|--|------------------------|--|-----------------|--|
| U.S. Department of Commerce, Patent and Trademark |  |  |  | Atty. Docket No.       |  | Application No. |  |
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|   |  |  |  | Applicant(s)           |  | Conf. No.       |  |
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|   |  |  |  | Filing Date            |  | Group           |  |
|   |  |  |  | July 24, 2003          |  | 2877            |  |

| U.S. Patent Documents |    |                 |       |                  |       |          |                            |
|-----------------------|----|-----------------|-------|------------------|-------|----------|----------------------------|
| *Examiner Initial     |    | Document Number | Date  | Name             | Class | Subclass | Filing Date If Appropriate |
|                       | AA | 4,589,773       | 5/86  | Ido et al.       |       |          |                            |
|                       | AB | 4,740,079       | 04/88 | Koizumi et al.   |       |          |                            |
|                       | AC | 4,966,457       | 10/90 | Hayano et al.    |       |          |                            |
|                       | AD | 5,125,741       | 6/92  | Okada et al.     |       |          |                            |
|                       | AE | 5,189,481       | 2/93  | Jann et al.      |       |          |                            |
|                       | AF | 5,245,403       | 9/93  | Kato et al.      |       |          |                            |
|                       | AG | 5,465,145       | 11/95 | Nakashige et al. |       |          |                            |

| U.S. Published Patent Application Documents |  |                 |      |      |       |          |                            |
|---|--|-----------------|------|------|-------|----------|----------------------------|
| *Examiner Initial                           |  | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|   |  |                 |      |      |       |          |                            |
|   |  |                 |      |      |       |          |                            |

| Foreign Patent Documents |    |            |         |               |       |          |             |    |
|--------------------------|----|------------|---------|---------------|-------|----------|-------------|----|
|                          |    |            |         |               |       |          | Translation |    |
|                          |    | Document   | Date    | Country       | Class | Subclass | Yes         | No |
|                          | AH | WO96/15354 | 9/25/96 | International |       |          | X           |    |
|                          | AI | WO97/04134 | 3/5/97  | International |       |          | X           |    |
|                          | AJ | WO99/14575 | 3/99    | International |       |          | X           |    |
|                          |    |            |         |               |       |          |             |    |

| OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) |    |  |
|--|----|--|
|  | AK | Search Report Corresponding to PCT Application No. PCT/US98/19564 issued by the International Patent Office on February 8, 1999. |
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| Examiner | Date Considered |
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

